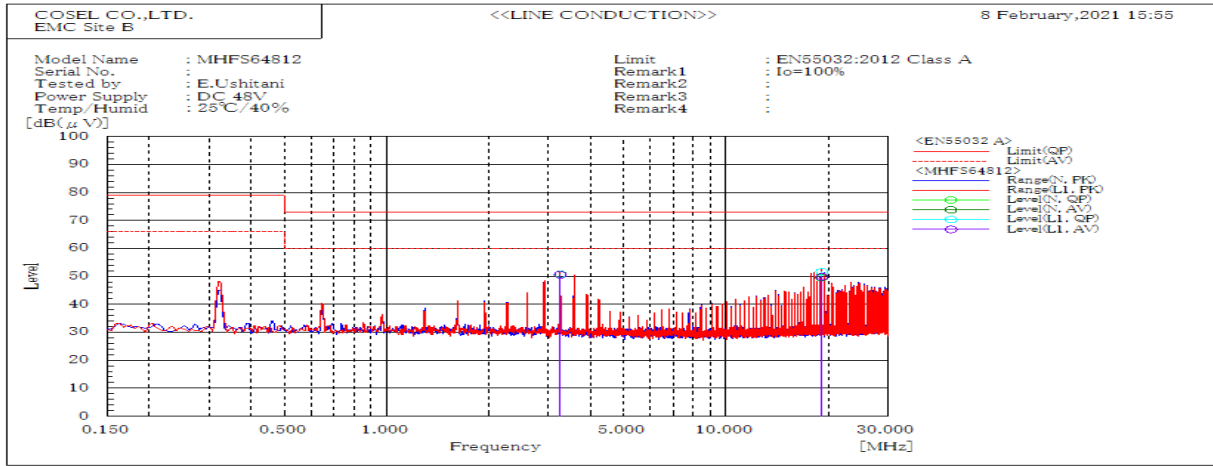
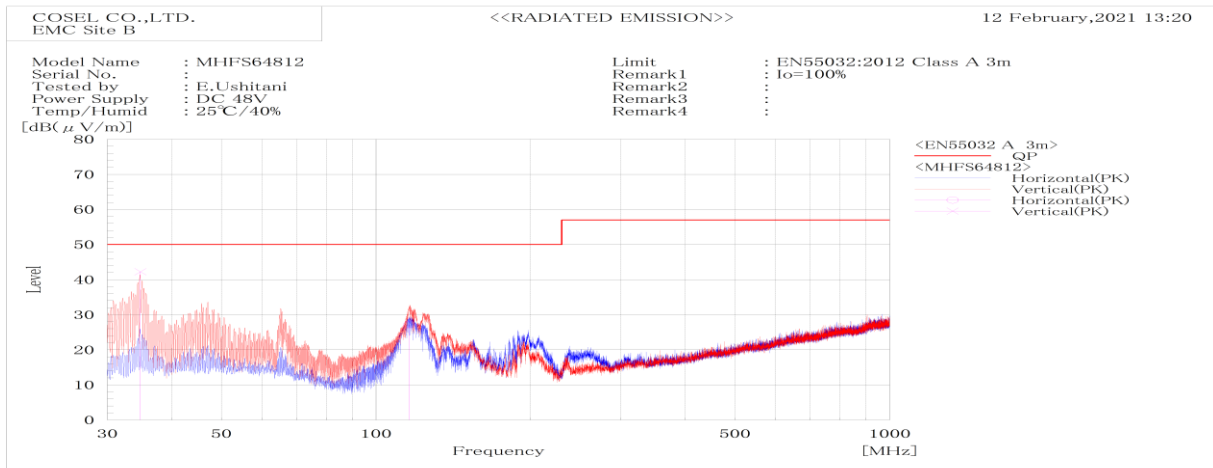


DATA SHEET		Date	05-Nov-21
Model	MHFS64812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



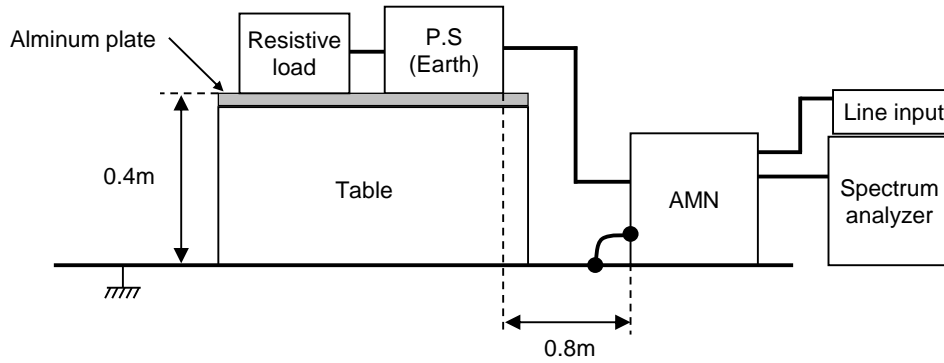
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
19.16	N	51.6	49.5	73	60	21.4	10.5	Pass	
3.247	N	50.8	50.7	73	60	22.2	9.3	Pass	
19.155	L1	51.7	49.9	73	60	21.3	10.1	Pass	
3.246	L1	50.7	50.6	73	60	22.3	9.4	Pass	



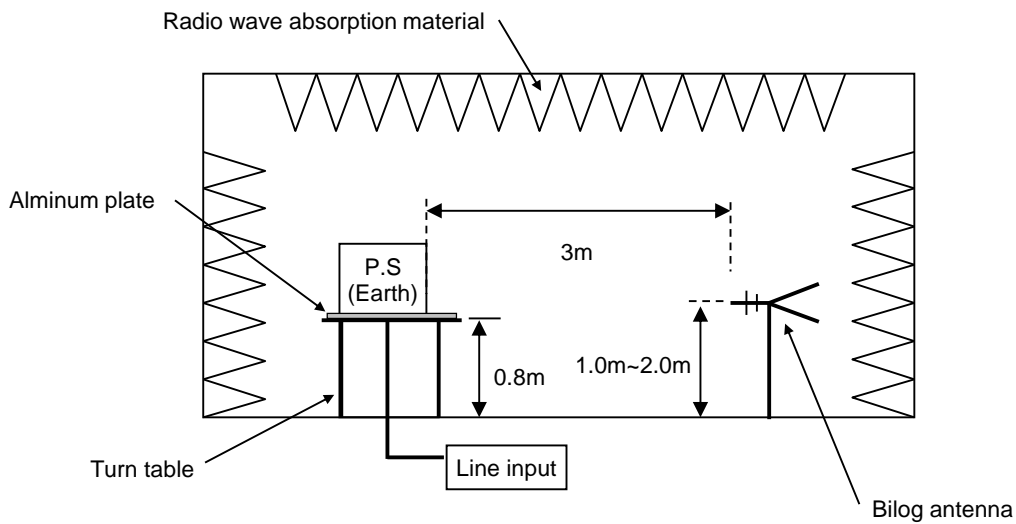
Frequency MHz	Polarization	Stability	Level dB(uV/m)		Limit dB(uV/m)		Margin dB		Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP	QP						
116.036	H	Stable	27.2	50	22.8	Pass	180.1	0				
34.785	V	Stable	42.3	50	7.7	Pass	100	205.8				

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission

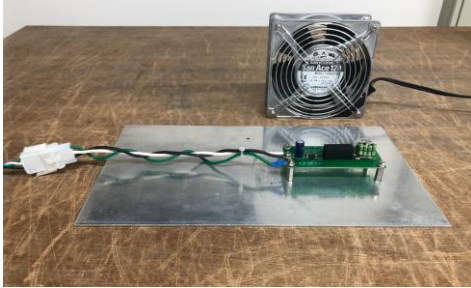


Conditions

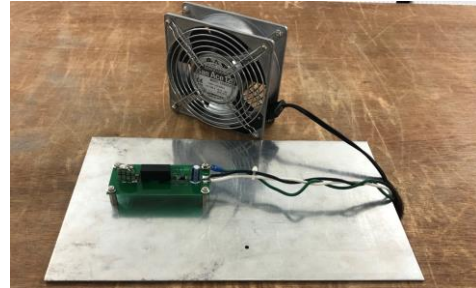
Test : EMI
 Model Name: MHFS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

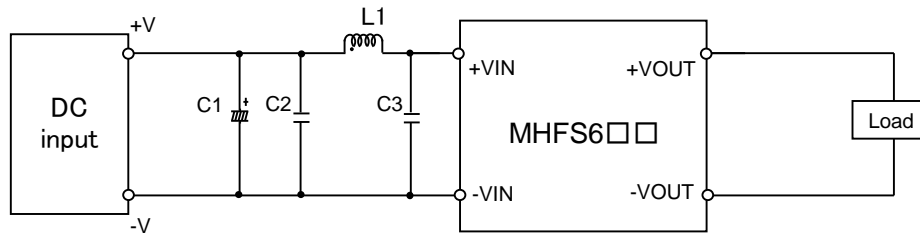


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 μ H Inductor(LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 μ H Inductor(LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 μ H Inductor(LQH5BPN220MT0 MURATA MANUFACTURING)